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| APPLICATION NO.   | FILING DATE      | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO |
|---|------------------|----------------------|---------------------|-----------------|
| 10/808,000  | 03/24/2004       | Scan T. Baartmans    | 42P16957            | 4660            |
| 8791 7  | 590 09/27/2006   |                      | EXAMINER            |                 |
| BLAKELY SOKOLOFF TAYLOR & ZAFMAN 12400 WILSHIRE BOULEVARD |                  |                      | BONURA, TIMOTHY M   |                 |
|   | SEVENTH FLOOR    |                      |                     | PAPER NUMBER    |
| LOS ANGELE  | S, CA 90025-1030 | 2114                 |                     |                 |

DATE MAILED: 09/27/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

|   | Application No.   | Applicant(s)   |  |  |  |  |
|---|---|--|--|--|--|--|
|   | 10/808,000  | BAARTMANS ET AL.   |  |  |  |  |
| Office Action Summary   | Examiner  | Art Unit   |  |  |  |  |
|   | Tim Bonura  | 2114   |  |  |  |  |
| The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply  |   |  |  |  |  |  |
| A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING D.  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period v.  - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).   | ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE | N. nely filed the mailing date of this communication. D (35 U.S.C. § 133). |  |  |  |  |
| Status  |   |  |  |  |  |  |
| 1) Responsive to communication(s) filed on <u>24 March 2004</u> .   |   |  |  |  |  |  |
| ·—  | ·   |  |  |  |  |  |
| ,   | 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is  |  |  |  |  |  |
| closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.   |   |  |  |  |  |  |
| Disposition of Claims   |   |  |  |  |  |  |
| 4) ☐ Claim(s) 1-32 is/are pending in the application. 4a) Of the above claim(s) is/are withdray 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-32 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/o  | wn from consideration.  |  |  |  |  |  |
| Application Papers  |   |  |  |  |  |  |
| 9) The specification is objected to by the Examine  |   |  |  |  |  |  |
| 10)⊠ The drawing(s) filed on <u>24 March 2004</u> is/are: a)⊠ accepted or b)  objected to by the Examiner.  |   |  |  |  |  |  |
| Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).   |   |  |  |  |  |  |
| Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).  11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.  |   |  |  |  |  |  |
| Priority under 35 U.S.C. § 119  |   |  |  |  |  |  |
| <ul> <li>12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some * c) None of:</li> <li>1. Certified copies of the priority documents have been received.</li> <li>2. Certified copies of the priority documents have been received in Application No</li> <li>3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul> |   |  |  |  |  |  |
| Attachment(s)  1) Notice of References Cited (PTO-892)  | 4) 🔲 Interview Summary  | (PTO-413)  |  |  |  |  |
| 2) Notice of Preferences Cited (PTO-992)  Notice of Draftsperson's Patent Drawing Review (PTO-948)  Information Disclosure Statement(s) (PTO/SB/08)  Paper No(s)/Mail Date  | Paper No(s)/Mail Do 5) Notice of Informal F 6) Other:   | ate  |  |  |  |  |

Art Unit: 2114

#### **DETAILED ACTION**

• Claim 6, 11, 12 and 14 are rejected under 35 U.S.C. 112, second paragraph

 Claims 1-5, 7-10, 13, and 15-32 are rejected under 35 U.S.C. 102(e) as being anticipated by Shinmori, et al, U.S. Patent Number 7,058,856

## Claim Rejections - 35 USC § 112

- 1. The following is a quotation of the second paragraph of 35 U.S.C. 112:
  - The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.
- 2. Claims 6, 11, 12, and 14 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.
- 3. Claim 6 recites the limitation "the test mode unit" in the second line of the claim. There is insufficient antecedent basis for this limitation in the claim.
- 4. Claim 11, 12, and 14 recite the limitation "the received external signals" in the claims.

  There is insufficient antecedent basis for this limitation in the claims.

## Claim Rejections - 35 USC § 102

5. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Art Unit: 2114

6. Claims 1-5, 7-10, 13, and 15-32 are rejected under 35 U.S.C. 102(e) as being anticipated by Shinmori, et al, U.S. Patent Number 7,058,856.

# 7. Regarding claim 1:

- a. Regarding the limitation of "a logic structure integrated in an integrated circuit (IC), the logic structure having a set of bus inputs to generate events, a mask register to select inputs from among the set of bus inputs, a logic register to select logic to apply to the selected inputs and an event output to supply the result of the applied logic," Shinmori discloses a system with a semiconductor circuit with a memory device storing a program and data, a CPU to execute the process of the program and to store the data on the Flash ROM (Lines 10-15 of Column 2 also see Figure 5).
- b. Regarding the limitation of "a bus interface integrated in the IC and coupled to the logic structure to transmit settable parameters to the mask register and the logic register of the logic structure from an external agent," Shinmori discloses a system with control signals select the first input to the JTAG. (Lines 55-60 of Column 5).
- 8. Regarding claim 2, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM for what data is received and selected for comparing. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 9. Regarding claim 3, Shinmori discloses a system with a cmp register for comparing (Figure 5, item 27 and 24, Lines 38-46 of Column 5).
- 10. Regarding claim 4, Shinmori discloses a system with a TAP (test access port) coupled to a bus, the TAP used for testing and debugging of data through the CPU. (See Figure 5, item 14 with input bus from the left of the box, also Lines 60-65 of Column 5).
- 11. Regarding claim 5, Shinmori discloses a system with a sel logic to select data from the TAP or the CPU. (Figure 5, item 22, Lines 17-23 of Column 6).

Art Unit: 2114

12. Regarding claim 7, Shinmori discloses a system with a JTAG port for receive test data and a control circuit for controlling the received data. (Lines 50-65 of Column 5, see Figure 5, items 23, 12, and 11).

- 13. Regarding claim 8, Shinmori discloses a system with a JTAG port for communicating a TDO (test output data) to the external device for testing. (Lines 65-67 of Column 4 and Lines 1-2 of Column 5).
- 14. Regarding claim 9, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 15. Regarding claim 10:
  - c. Regarding the limitation of "a counter register integrated in an integrated circuit and couple with an external unit integrated in the IC to receive results of operation from the external unit," Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
  - d. Regarding the limitation of "a logic structure integrated in the IC to receive signals from the external unit, to send operation to the external unit, to generate events based on the received external signals and received settable parameters, and to send the events to the counter register to after the operation of the counter register," Shinmori discloses a system with a semiconductor circuit with a memory device storing a program and data, a CPU to execute the process of the program and to store the data on the Flash ROM (Lines 10-15 of Column 2 also see Figure 5). Shinmori discloses a system with a TAP (test access port) coupled to a bus, the TAP used for testing and debugging of data through the CPU. (See Figure 5, item 14 with input bus from the left of the box,

Art Unit: 2114

also Lines 60-65 of Column 5). External signals are received at eh JTAG port from a debugging device. (Lines 64-67 of Column 4).

- e. Regarding the limitation of "a bus interface integrated in the IC and coupled to the logic structure to transmit settable parameters to the mask register and the logic register of the logic structure from an external agent," Shinmori discloses a system with control signals select the first input to the JTAG. (Lines 55-60 of Column 5).
- 16. Regarding claim 13, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM for what data is received and selected for comparing. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 17. Regarding claim 15, Shinmori discloses a system with a clock signal that is inputting through the JTAG port. (Figure 5, item 11, the TCK signal).
- 18. Regarding claim 16, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 19. Regarding claim 17, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 20. Regarding claim 18:
  - f. Regarding the limitation of "receiving settable of parameters in a logic structure of an integrated circuit (IC)," Shinmori discloses a system a JTAG port for receiving parameters to be debugged. (See Figure 5, and Lines 64-67 of Column 4 and Lines 1-7 of Column 5).
  - g. Regarding the limitation of "receiving a set of bus inputs in the logic structure of the IC," Shinmori discloses a system a JTAG port for receiving data. (See Figure 5, and Lines 64-67 of Column 4 and Lines 1-7 of Column 5).

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Art Unit: 2114

h. Regarding the limitation of "applying logic to the selected bus inputs in the logic structure to generate an event," Shinmori discloses a system with a TAP (test access port) coupled to a bus, the TAP used for testing and debugging of data through the CPU. (See Figure 5, item 14 with input bus from the left of the box, also Lines 60-65 of Column 5).

- i. Regarding the limitation of "applying the events to a counter structure," Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 21. Regarding claim 19, Shinmori discloses a system with a JTAG port for communicating a TDO (test output data) to the external device for testing. (Lines 65-67 of Column 4 and Lines 1-2 of Column 5).
- 22. Regarding claim 20, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM for what data is received and selected for comparing. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 23. Regarding claim 21, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 24. Regarding claim 22, Shinmori discloses a system with a cmp register for comparing (Figure 5, item 27 and 24, Lines 38-46 of Column 5).
- 25. Regarding claim 23, Shinmori discloses a system with a sel logic to select data from the TAP or the CPU. (Figure 5, item 22, Lines 17-23 of Column 6).
- 26. Regarding claim 24:
  - j. Regarding the limitation of "receiving settable of parameters in a logic structure of an integrated circuit (IC)," Shinmori discloses a system a JTAG port for receiving

Art Unit: 2114

parameters to be debugged. (See Figure 5, and Lines 64-67 of Column 4 and Lines 1-7 of Column 5).

- k. Regarding the limitation of "receiving a set of bus inputs in the logic structure of the IC," Shinmori discloses a system a JTAG port for receiving data. (See Figure 5, and Lines 64-67 of Column 4 and Lines 1-7 of Column 5).
- I. Regarding the limitation of "applying logic to the selected bus inputs in the logic structure to generate an event," Shinmori discloses a system with a TAP (test access port) coupled to a bus, the TAP used for testing and debugging of data through the CPU. (See Figure 5, item 14 with input bus from the left of the box, also Lines 60-65 of Column 5).
- m. Regarding the limitation of "generating a system management interrupt based on the event," Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 27. Regarding claim 25, Shinmori discloses a system with a JTAG port for communicating a TDO (test output data) to the external device for testing. (Lines 65-67 of Column 4 and Lines 1-2 of Column 5).
- 28. Regarding claim 26, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM for what data is received and selected for comparing. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 29. Regarding claim 27, Shinmori discloses a system with a cmp register for comparing (Figure 5, item 27 and 24, Lines 38-46 of Column 5).
- 30. Regarding claim 28, Shinmori discloses a system with a sel logic to select data from the TAP or the CPU. (Figure 5, item 22, Lines 17-23 of Column 6).
- 31. Regarding claim 29:

Art Unit: 2114

n. Regarding the limitation of "receiving a set of bus inputs in a logic structure of an integrated circuit (IC)," Shinmori discloses a system a JTAG port for receiving parameters to be debugged. (See Figure 5, and Lines 64-67 of Column 4 and Lines 1-7 of Column 5).

- o. Regarding the limitation of "applying a mask in the logic structure to select inputs from among the bus inputs," Shinmori discloses a system a JTAG port for receiving data. (See Figure 5, and Lines 64-67 of Column 4 and Lines 1-7 of Column 5). Shinmori discloses a system with a sel logic to select data from the TAP or the CPU. (Figure 5, item 22, Lines 17-23 of Column 6).
- p. Regarding the limitation of "applying logic to the selected bus inputs in the logic structure to generate an event," Shinmori discloses a system with a TAP (test access port) coupled to a bus, the TAP used for testing and debugging of data through the CPU. (See Figure 5, item 14 with input bus from the left of the box, also Lines 60-65 of Column 5).
- q. Regarding the limitation of "generating a system management interrupt based on the event," Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- r. Regarding the limitation of "applying the events to a counter structure," Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- s. Regarding the limitation of "providing the events over a bus to an external agent,"
  Shinmori discloses a system with a JTAG port for communicating a TDO (test output data) to the external device for testing. (Lines 65-67 of Column 4 and Lines 1-2 of Column 5).

Art Unit: 2114

32. Regarding claim 30, Shinmori discloses a system with a JTAG port for receive test data and a control circuit for controlling the received data. (Lines 50-65 of Column 5, see Figure 5, items 23, 12, and 11).

- 33. Regarding claim 31, Shinmori discloses a system with a security bit that can be used to manage the data in the flash ROM for what data is received and selected for comparing. (Lines 65-67 of Column 5 and Lines 1-12 of Column 6).
- 34. Regarding claim 32, Shinmori discloses a system with a cmp register for comparing (Figure 5, item 27 and 24, Lines 38-46 of Column 5).

## Claim Objections

35. The numbering of claims is not in accordance with 37 CFR 1.126 which requires the original numbering of the claims to be preserved throughout the prosecution. When claims are canceled, the remaining claims must not be renumbered. When new claims are presented, they must be numbered consecutively beginning with the number next following the highest numbered claims previously presented (whether entered or not). Claims 11, 12, and 14 do not follow proper claim numbering. Please correct the numbering issues.

### Conclusion

- 36. Any inquiry concerning this communication or earlier communications from the examiner should be directed to **Tim Bonura**.
  - The examiner can normally be reached on Mon-Fri: 8:30-5:00.
  - The examiner can be reached at: 571-272-3654.
- 37. If attempts to reach the examiner by telephone are unsuccessful, please contact the examiner's supervisor, **Scott Baderman**.

Art Unit: 2114

o The supervisor can be reached on 571-272-3644.

38. The fax phone numbers for the organization where this application or proceeding is

assigned are:

o 703-872-9306 for all patent related correspondence by FAX.

39. Information regarding the status of an application may be obtained from the Patent

Application Information Retrieval (PAIR) system. Status information for published applications

may be obtained from either Private PAIR or Public PAIR. Status information for unpublished

applications is available through Private PAIR only. For more information about the PAIR

system, see <a href="http://pair-direct.uspto.gov/">http://pair-direct.uspto.gov/</a>. Should you have questions on access to the Private

PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

40. Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is: 571-272-2100.

**41.** Responses should be mailed to:

o Commissioner of Patents and Trademarks

P.O. Box 1450

Alexandria, VA 22313-1450

Tim Bonura Examiner Art Unit 2114

September 22, 2006

